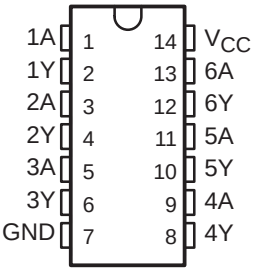
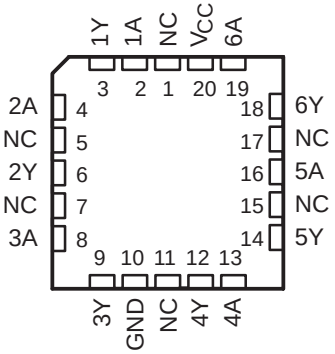
- ***EPIC***™ **(Enhanced-Performance Implanted CMOS) Submicron Process**
- **Inputs and Open-Drain Outputs Accept Voltages Up to 5.5 V**
- **Latch-Up Performance Exceeds 250 mA Per JESD 17**
- **Package Options Include Plastic Small-Outline (D), Thin Very Small-Outline (DGV), Thin Shrink Small-Outline (PW) Packages, and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and DIPs (J)**

SN54LVC07A . . . J OR W PACKAGE
SN74LVC07A . . . D, DGV, OR PW PACKAGE
(TOP VIEW)



SN54LVC07A . . . FK PACKAGE
(TOP VIEW)



NC – No internal connection

description

These hex buffers/drivers are designed for 1.65-V to 5.5-V V_{CC} operation.

The outputs of the ’LVC07A devices are open drain and can be connected to other open-drain outputs to implement active-low wired-OR or active-high wired-AND functions. The maximum sink current is 24 mA.

Inputs can be driven from 1.8-V, 2.5-V, 3.3-V (LVTTL), or 5-V (CMOS) devices. This feature allows the use of these devices as translators in a mixed-system environment.

The SN54LVC07A is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74LVC07A is characterized for operation from –40°C to 85°C.

FUNCTION TABLE
(each buffer/driver)

INPUT A	OUTPUT Y
H	H
L	L

Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

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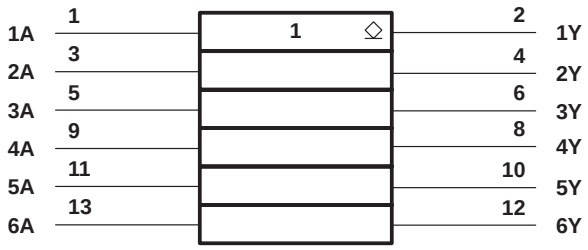
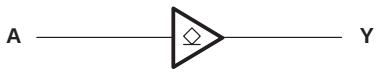
logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.
Pin numbers shown are for the D, DGV, J, PW, and W packages.

logic diagram, each buffer/driver (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V_{CC} . . . . . –0.5 V to 6.5 V
Input voltage range, V_I (see Note 1) . . . . . –0.5 V to 6.5 V
Output voltage range, V_O . . . . . –0.5 V to 6.5 V
Input clamp current, I_{IK} (V_I < 0) . . . . . –50 mA
Output clamp current, I_{OK} (V_O < 0) . . . . . –50 mA
Continuous output current, I_O . . . . . ±50 mA
Continuous current through V_{CC} or GND . . . . . ±100 mA
Package thermal impedance, θ_{JA} (see Note 2): D package . . . . . 127°C/W
DGV package . . . . . 182°C/W
PW package . . . . . 170°C/W
Storage temperature range, T_{stg} . . . . . –65°C to 150°C

‡ Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 3)

			SN54LVC07A		SN74LVC07A		UNIT
			MIN	MAX	MIN	MAX	
V_{CC}	Supply voltage		1.65	5.5	1.65	5.5	V
V_{IH}	High-level input voltage	V_{CC} = 1.65 V to 1.95 V	$0.65 \times V_{CC}$		$0.65 \times V_{CC}$		V
		V_{CC} = 2.3 V to 2.7 V	1.7		1.7		
		V_{CC} = 2.7 V to 3.6 V	2		2		
		V_{CC} = 4.5 V to 5.5 V	$0.7 \times V_{CC}$		$0.7 \times V_{CC}$		
V_{IL}	Low-level input voltage	V_{CC} = 1.65 V to 1.95 V		$0.35 \times V_{CC}$		$0.35 \times V_{CC}$	V
		V_{CC} = 2.3 V to 2.7 V		0.7		0.7	
		V_{CC} = 2.7 V to 3.6 V		0.8		0.8	
		V_{CC} = 4.5 V to 5.5 V		$0.3 \times V_{CC}$		$0.3 \times V_{CC}$	
V_I	Input voltage		0	5.5	0	5.5	V
V_O	Output voltage		0	5.5	0	5.5	V
I_{OL}	Low-level output current	V_{CC} = 1.65 V		4		4	mA
		V_{CC} = 2.3 V		12		12	
		V_{CC} = 2.7 V		12		12	
		V_{CC} = 3 V		24		24	
		V_{CC} = 4.5 V		24		24	
T_A	Operating free-air temperature		–55	125	–40	85	°C

PRODUCT PREVIEW

NOTE 3: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V_{CC}	SN54LVC07A			SN74LVC07A			UNIT
			MIN	TYP†	MAX	MIN	TYP†	MAX	
V_{OL}	I_{OL} = 100 μA	1.65 V to 5.5 V			0.2			0.2	V
	I_{OL} = 4 mA	1.65 V			0.45			0.45	
	I_{OL} = 12 mA	2.3 V			0.7			0.7	
		2.7 V			0.4			0.4	
	I_{OL} = 24 mA	3 V			0.55			0.55	
		4.5 V							
I_I	V_I = 5.5 V or GND	3.6 V			±5			±5	μA
I_{CC}	$V_I = V_{CC}$ or GND, I_O = 0	3.6 V			10			10	μA
ΔI_{CC}	One input at V_{CC} – 0.6 V, Other inputs at V_{CC} or GND	2.7 V to 3.6 V			500			500	μA
C_i	$V_I = V_{CC}$ or GND	3.3 V		5			5		pF

† All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

PRODUCT PREVIEW

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switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 4)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	SN54LVC07A										UNIT
			V_{CC} = 1.8 V ± 0.15 V		V_{CC} = 2.5 V ± 0.2 V		V_{CC} = 2.7 V		V_{CC} = 3.3 V ± 0.3 V		V_{CC} = 5 V ± 0.5 V		
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
t_{pd}	A	Y	1	3.5	1	2.8		3	1	2.9	1	2.6	ns

PRODUCT PREVIEW

switching characteristics over recommended operating free-air temperature range, (unless otherwise noted) (see Figures 1 through 4)

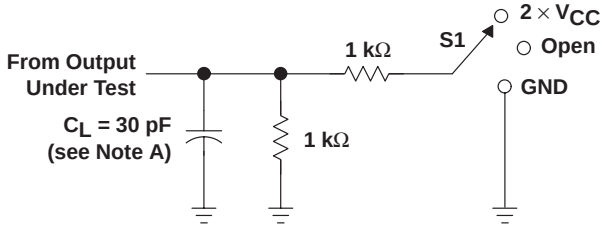
PARAMETER	FROM (INPUT)	TO (OUTPUT)	SN74LVC07A										UNIT
			V_{CC} = 1.8 V ± 0.15 V		V_{CC} = 2.5 V ± 0.2 V		V_{CC} = 2.7 V		V_{CC} = 3.3 V ± 0.3 V		V_{CC} = 5 V ± 0.5 V		
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
t_{pd}	A	Y	1	3.5	1	2.8		3	1	2.9	1	2.6	ns

operating characteristics, T_A = 25°C

PARAMETER		TEST CONDITIONS	V_{CC} = 1.8 V ± 0.15 V	V_{CC} = 2.5 V ± 0.2 V	V_{CC} = 3.3 V ± 0.3 V	V_{CC} = 5 V ± 0.5 V	UNIT
			TYP	TYP	TYP	TYP	
C_{pd}	Power dissipation capacitance per buffer/driver	f = 10 MHz	1.8	2	2.5	3.78	pF

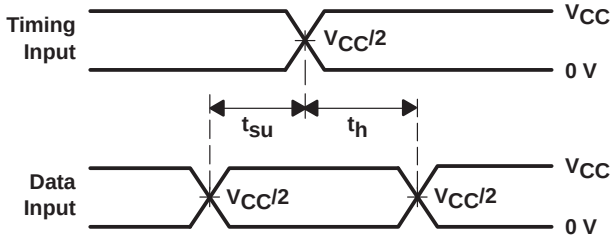
PRODUCT PREVIEW information concerns products in the formative or design phase of development. Characteristic data and other specifications are design goals. Texas Instruments reserves the right to change or discontinue these products without notice.

PARAMETER MEASUREMENT INFORMATION
V_{CC} = 1.8 V ± 0.15 V

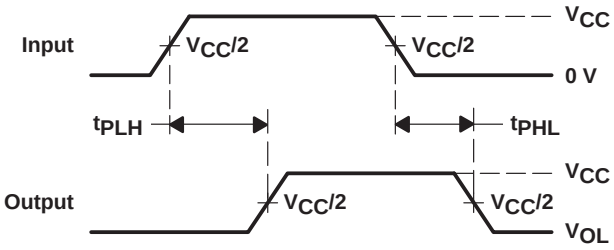


TEST	S1
t_{PZL} (see Note F)	2 × V_{CC}
t_{PLZ} (see Note G)	2 × V_{CC}
t_{PHZ}/t_{PZH}	2 × V_{CC}

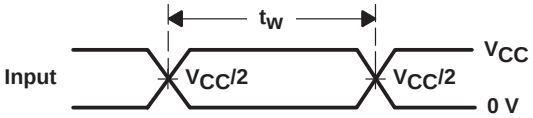
LOAD CIRCUIT



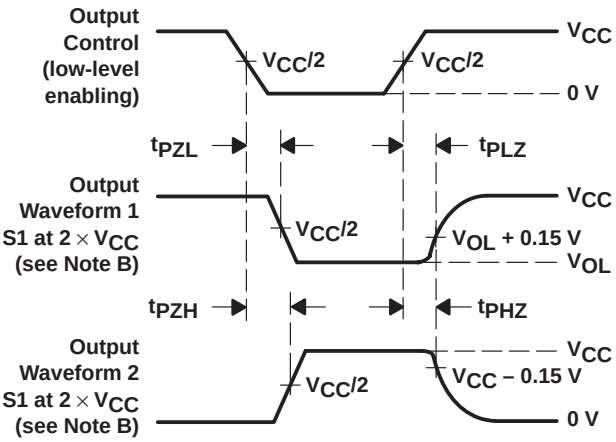
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION

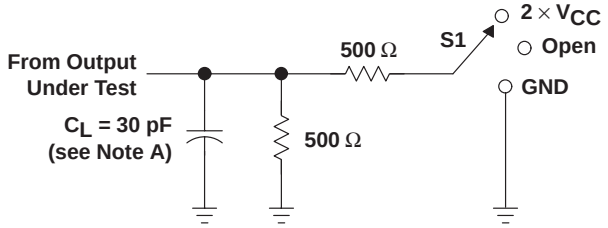


VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

NOTES: A. C_L includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, Z_O = 50 Ω, t_r ≤ 2 ns, t_f ≤ 2 ns.
D. The outputs are measured one at a time with one transition per measurement.
E. Since this device has open-drain outputs, t_{PLZ} and t_{PZL} are the same as t_{pd}.
F. t_{PZL} is measured at $V_{CC}/2$.
G. t_{PLZ} is measured at V_{OL} + 0.15 V.

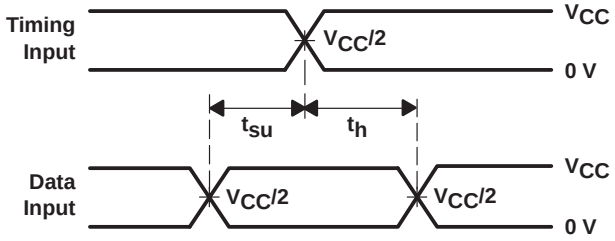
Figure 1. Load Circuit and Voltage Waveforms

PARAMETER MEASUREMENT INFORMATION
V_{CC} = 2.5 V ± 0.2 V

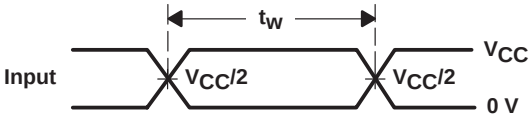


LOAD CIRCUIT

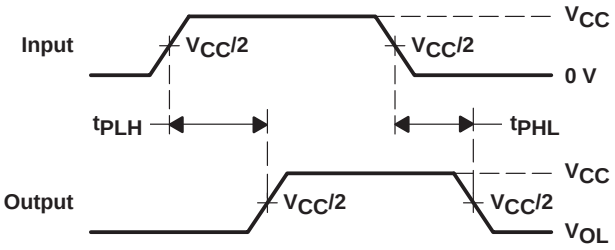
TEST	S1
t_{PZL} (see Note F)	2 × V_{CC}
t_{PLZ} (see Note G)	2 × V_{CC}
t_{PHZ}/t_{PZH}	2 × V_{CC}



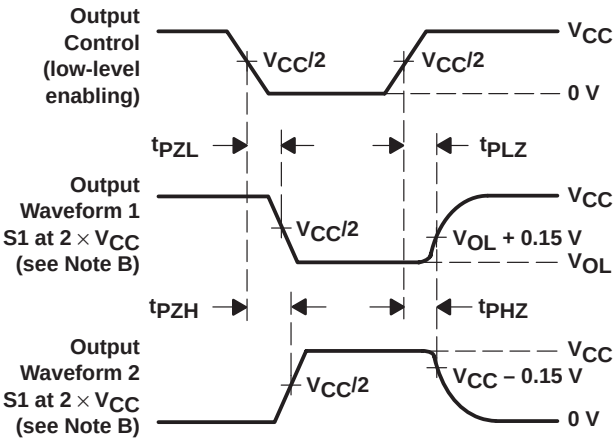
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES

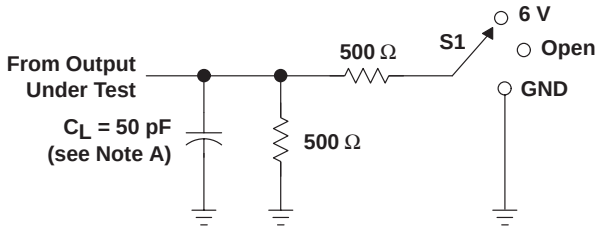


VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

NOTES: A. C_L includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, Z_O = 50 Ω, t_r ≤ 2 ns, t_f ≤ 2 ns.
D. The outputs are measured one at a time with one transition per measurement.
E. Since this device has open-drain outputs, t_{PLZ} and t_{PZL} are the same as t_{pd}.
F. t_{PZL} is measured at $V_{CC}/2$.
G. t_{PLZ} is measured at V_{OL} + 0.15 V.

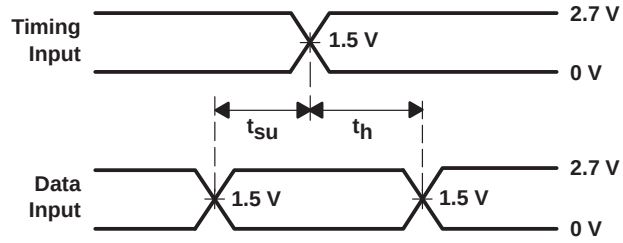
Figure 2. Load Circuit and Voltage Waveforms

PARAMETER MEASUREMENT INFORMATION
V_{CC} = 2.7 AND 3.3 V ± 0.3 V

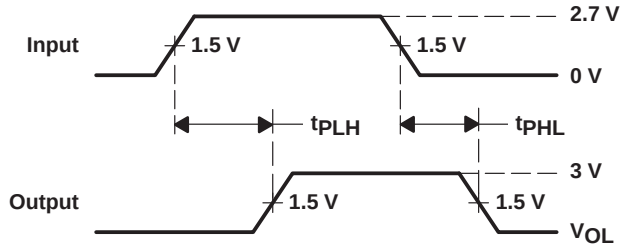


LOAD CIRCUIT

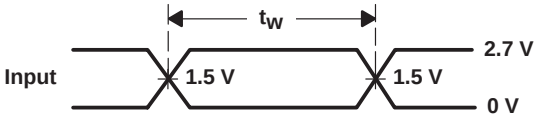
TEST	S1
t_{PZL} (see Note F)	6 V
t_{PLZ} (see Note G)	6 V
t_{PHZ}/t_{PZH}	6 V



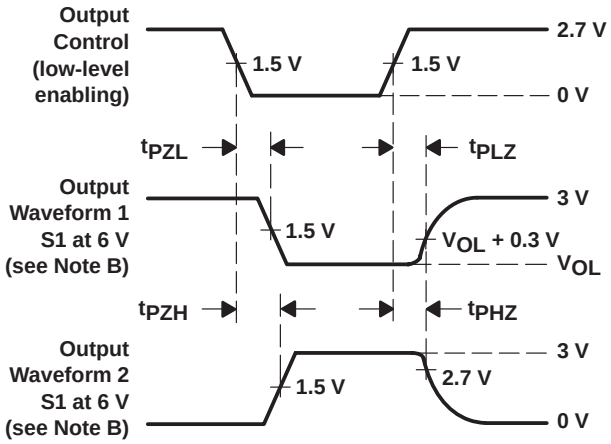
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION

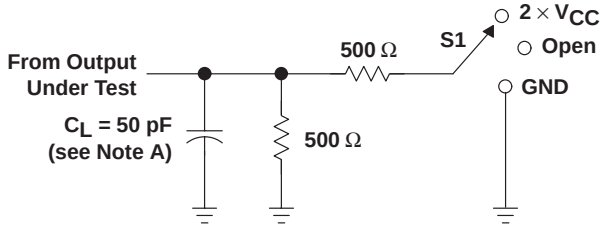


VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

NOTES: A. C_L includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, Z_O = 50 Ω, t_r ≤ 2.5 ns, t_f ≤ 2.5 ns.
D. The outputs are measured one at a time with one transition per measurement.
E. Since this device has open-drain outputs, t_{PLZ} and t_{PZL} are the same as t_{pd}.
F. t_{PZL} is measured at 1.5 V.
G. t_{PLZ} is measured at V_{OL} + 0.3 V.

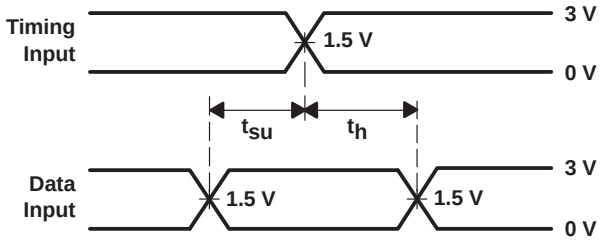
Figure 3. Load Circuit and Voltage Waveforms

PARAMETER MEASUREMENT INFORMATION
V_{CC} = 5 V ± 0.5 V

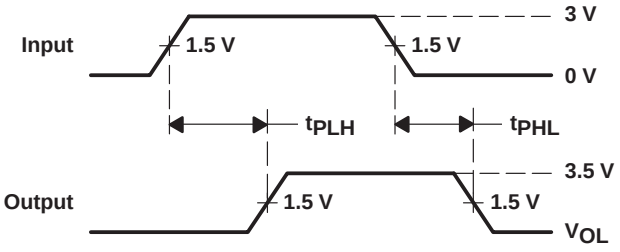


TEST	S1
t_{PZL} (see Note F)	2 × V_{CC}
t_{PLZ} (see Note G)	2 × V_{CC}
t_{PHZ}/t_{PZH}	7 V

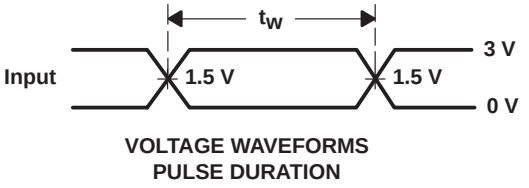
LOAD CIRCUIT



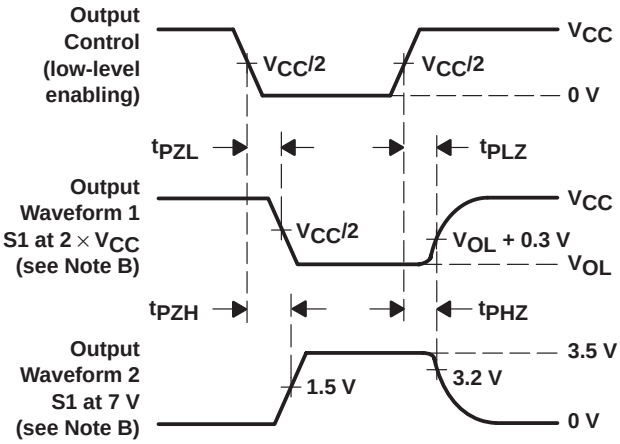
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

NOTES: A. C_L includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, Z_O = 50 Ω, t_r ≤ 2.5 ns, t_f ≤ 2.5 ns.
D. The outputs are measured one at a time with one transition per measurement.
E. Since this device has open-drain outputs, t_{PLZ} and t_{PZL} are the same as t_{pd}.
F. t_{PZL} is measured at $V_{CC}/2$.
G. t_{PLZ} is measured at V_{OL} + 0.3 V.

Figure 4. Load Circuit and Voltage Waveforms

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